

MCP4821/MCP4822

12-Bit DACs with Internal V_{REF} and SPI^M Interface

Features

- 12-Bit Resolution
- ±0.2 LSb DNL (typ.)
- ±2 LSb INL (typ.)
- Single or Dual Channel
- Rail-to-Rail Output
- SPI™ Interface with 20 MHz Clock Support
- Simultaneous Latching of the Dual DACs with LDAC pin
- Fast Settling Time of 4.5 µs
- · Selectable Unity or 2x Gain Output
- 2.048V Internal Band Gap Voltage Reference
- 50 ppm/°C V_{REF} Temperature Coefficient
- 2.7V to 5.5V Single-Supply Operation
- Extended Temperature Range: -40°C to +125°C

Applications

- Set Point or Offset Trimming
- Sensor Calibration
- Precision Selectable Voltage Reference
- Portable Instrumentation (Battery-Powered)
- Calibration of Optical Communication Devices

Block Diagram



Description

The Microchip Technology Inc. MCP482X devices are 2.7V–5.5V, low-power, low DNL, 12-bit Digital-to-Analog Converters (DACs) with internal band gap voltage reference, optional 2x-buffered output and Serial Peripheral Interface (SPI[™]).

The MCP482X family of DACs provide high accuracy and low noise performance for industrial applications where calibration or compensation of signals (such as temperature, pressure and humidity) are required.

The MCP482X devices are available in the extended temperature range and PDIP, SOIC and MSOP packages.

The MCP482X devices utilize a resistive string architecture, with its inherent advantages of low DNL error, low ratio metric temperature coefficient and fast settling time. These devices are specified over the extended temperature range. The MCP482X family includes double-buffered registers, allowing simultaneous updates using the LDAC pin. These devices also incorporate a Power-On Reset (POR) circuit to ensure reliable power-up.

Package Types



1.0 ELECTRICAL CHARACTERISTICS

Absolute Maximum Ratings †

V _{DD}
All inputs and outputsAV_{SS} – 0.3V to V_{DD} + 0.3V
Current at Input Pins±2 mA
Current at Supply Pins±50 mA
Current at Output Pins±25 mA
Storage temperature65°C to +150°C
Ambient temp. with power applied55°C to +125°C
ESD protection on all pins \geq 4 kV (HBM), \geq 400V (MM)
Maximum Junction Temperature (T _J)+150°C

† Notice: Stresses above those listed under "Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at those or any other conditions above those indicated in the operational listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

5V AC/DC CHARACTERISTICS

Electrical Specifications: Unless otherwise indicated, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, output buffer gain (G) = 2x, $R_L = 5 k\Omega$ to GND, $C_L = 100 \text{ pF}$, $T_A = -40 \text{ to } +85^{\circ}\text{C}$. Typical values at +25°C.

Parameters	Sym	Min	Тур	Max	Units	Conditions
Power Requirements	•				•	·
Input Voltage	V _{DD}	2.7	_	5.5		
Input Current - MCP4821 - MCP4822	I _{DD}		330 415	400 750	μA	Digital inputs grounded, Output unloaded, code = 0x000
Hardware Shutdown Current	I _{SHDN}	_	0.3	2	μA	
Software Shutdown Current	I _{SHDN_SW}	_	3.3	6	μA	
Power-on-Reset Threshold	V _{POR}		2.0		V	
DC Accuracy						
Resolution	n	12			Bits	
INL Error	INL	-12	2	12	LSb	
DNL (Note 1)	DNL	-0.75	±0.2	+0.75	LSb	Device is monotonic
Offset Error	V _{OS}	-1	±0.02	1	% of FSR	Code = 0x000h
Offset Error Temperature	V _{OS} /°C		0.16		ppm/°C	-45°C to 25°C
Coefficient			-0.44	_	ppm/°C	+25°C to 85°C
Gain Error	9 _E	-2	-0.10	2	% of FSR	Code 0xFFFh, not including offset error
Gain Error Temperature Coefficient	∆g/°c	—	-3	_	ppm/°C	
Internal Voltage Reference (V	_{REF})					
Nominal Reference Voltage	V _{REF}	2.008	2.048	2.088	V	V _{OUTA} when G = 1x and Code = 0xFFFh
Temperature Coefficient	ΔV_{REF} /°C	_	125	325	ppm/°C	-40°C to 0°C
(Note 1)		_	0.25	0.65	LSb/°C	-40°C to 0°C
		_	45	160	ppm/°C	0°C to +85°C
		_	0.09	0.32	LSb/°C	0°C to +85°C
Output Noise (V _{REF} Noise)	E _{NREF} (0.1-10 Hz)	_	290	_	μV _{p-p}	Code = 0xFFFh, G = 1
Output Noise Density	e _{NREF} (1 kHz)	—	1.2	—	µV/√Hz	Code = 0xFFFh, G = 1
	e _{NREF} (10 kHz)	_	1.0	_	µV/√Hz	Code = 0xFFFh, G = 1
1/f Corner Frequency	f _{CORNER}	—	400	_	Hz	

Note 1: By design, not production tested.

5V AC/DC CHARACTERISTICS (CONTINUED)

Parameters	Sym	Min	Тур	Max	Units	Conditions
Output Amplifier						
Output Swing	V _{OUT}	—	0.010 to V _{DD} -0.040	_		Accuracy is better than 1 LSb for $V_{OUT} = 10 \text{ mV}$ to $(V_{DD} - 40 \text{ mV})$
Phase Margin	PM	_	66	_	0	
Slew Rate	SR	_	0.55	_	V/µs	
Short Circuit Current	I _{SC}	_	15	24	mA	
Settling Time	t _{SETTLING}	_	4.5	_	μs	Within 1/2 LSb of final value from 1/4 to 3/4 full-scale range
Dynamic Performance						
DAC-to-DAC Crosstalk			<10	_	nV-s	Note 2
Major Code Transition Glitch			45	—	nV-s	1 LSb change around major carry (01111111 to 10000000)
Digital Feedthrough		_	<10	_	nV-s	Note 2
Analog Crosstalk		_	<10	_	nV-s	Note 2

Note 1: By design, not production tested.

2: Too small to quantify.

3V AC/DC CHARACTERISTICS

Electrical Specifications: Unless otherwise indicated, $V_{DD} = 3V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$ external, output buffer gain (G) = 1x, $R_L = 5 k\Omega$ to GND, $C_L = 100 \text{ pF}$, $T_A = -40 \text{ to } +85^{\circ}\text{C}$. Typical values at 25°C

$R_{L} = 5$ ks to GND, $C_{L} = 100$ pr; $R_{A} = -40$ to $+65$ C. Typical values at 25 C								
Parameters	Sym	Min	Тур	Max	Units	Conditions		
Power Requirements								
Input Voltage	V _{DD}	2.7	—	5.5				
Input Current - MCP4821 - MCP4822	I _{DD}		300 415	400 750	μA	Digital inputs grounded, Output unloaded, code = 0x000		
Hardware Shutdown Current	I _{SHDN}	_	0.25	2	μA			
Software Shutdown Current	I _{SHDN_SW}	_	2	6	μA			
Power-On Reset threshold	V _{POR}	_	2.0	—	V			
DC Accuracy								
Resolution	n	12	—	—	Bits			
INL Error	INL	-12	±3	12	LSb			
DNL (Note 1)	DNL	-0.75	±0.3	0.75	LSb	Device is monotonic		
Offset Error	V _{OS}	-1	±0.02	1	% of FSR	Code 0x000h		
Offset Error Temperature	V _{OS} /°C	_	0.5	_	ppm/°C	-45°C to +25°C		
Coefficient		_	-0.77	_	ppm/°C	+25°C to +85°C		
Gain Error	9 _E	-2	-0.15	2	% of FSR	Code 0xFFFh, not including off- set error		
Gain Error Temperature Coefficient	Δ G/°C	_	-3	—	ppm/°C			

Note 1: By design, not production tested.

3V AC/DC CHARACTERISTICS (CONTINUED)

Electrical Specifications: Unit $R_L = 5 k\Omega$ to GND, $C_L = 100 pR$					= 2.048V ext	ternal, output buffer gain (G) = 1x,
Parameters	Sym	Min	Тур	Max	Units	Conditions
Internal Voltage Reference (V	(_{REF})					
Nominal Reference Voltage	V _{REF}	2.008	2.048	2.088	V	V_{OUTA} when G = 1x and Code = 0xFFFh
Temperature Coefficient	ΔV_{REF} /°C	_	125	325	ppm/°C	-40°C to 0°C
(Note 1)		_	0.25	0.65	LSb/°C	-40°C to 0°C
		_	45	160	ppm/°C	0°C to +85°C
		_	0.09	0.32	LSb/°C	0°C to +85°C
Output Noise (V _{REF} Noise)	E _{NREF} (0.1-10 Hz)	_	290	_	μV _{p-p}	Code = 0xFFFh, G = 1
Output Noise Density	e _{NREF} (1 kHz)	—	1.2	—	µV/√Hz	Code = 0xFFFh, G = 1
	e _{NREF} (10 kHz)	—	1.0	—	µV/√Hz	Code = 0xFFFh, G = 1
1/f Corner Frequency	f _{CORNER}	_	400	_	Hz	
Output Amplifier						
Output Swing	V _{OUT}	—	0.010 to V _{DD} -0.040	—		Accuracy is better than 1 LSb for $V_{OUT} = 10 \text{ mV}$ to $(V_{DD} - 40 \text{ mV})$
Phase Margin	PM	_	66	_	0	
Slew Rate	SR	—	0.55	—	V/µs	
Short Circuit Current	I _{SC}	—	14	24	mA	
Settling Time	^t SETTLING	—	4.5	_	μs	Within 1/2 LSb of final value from 1/4 to 3/4 full-scale range
Dynamic Performance						
DAC-to-DAC Crosstalk		—	<10	_	nV-s	Note 2
Major Code Transition Glitch		_	45	—	nV-s	1 LSb change around major carry (01111111 to 10000000)
Digital Feedthrough		—	<10	_	nV-s	Note 2
Analog Crosstalk		_	<10	_	nV-s	Note 2

Note 1: By design, not production tested.

2: Too small to quantify.

5V EXTENDED TEMPERATURE SPECIFICATIONS

Electrical Specifications: Unless otherwise indicated, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, output buffer gain (G) = 2x, $R_L = 5 k\Omega$ to GND, $C_L = 100 \text{ pF}$. Typical values at +125°C by characterization or simulation.

Parameters	Sym	Min	Тур	Мах	Units	Conditions
Power Requirements						
Input Voltage	V _{DD}	2.7	_	5.5		
Input Current - MCP4821 - MCP4822	I _{DD}	_	350 440	—	μA	Digital inputs grounded, Output unloaded, code = 0x000
Hardware Shutdown Current	I _{SHDN}	—	1.5	—	μA	
Software Shutdown Current	I _{SHDN_SW}	_	5	—	μA	
Power-On Reset threshold	V _{POR}	_	1.85	—	V	
DC Accuracy						
Resolution	n	12	_	_	Bits	
INL Error	INL		±4	_	LSb	

Note 1: By design, not production tested.

5V EXTENDED TEMPERATURE SPECIFICATIONS (CONTINUED)

Electrical Specifications: Unless otherwise indicated, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, output buffer gain (G) = 2x, R_I = 5 k Ω to GND, C_I = 100 pF. Typical values at +125°C by characterization or simulation.

$R_L = 5 \text{ k}\Omega$ to GND, $C_L = 100 \text{ pH}$	F. Typical values	at +125°	°C by character	ization or	simulation.	
Parameters	Sym	Min	Тур	Max	Units	Conditions
DNL (Note 1)	DNL	_	±0.25	_	LSb	Device is monotonic
Offset Error	V _{OS}	_	±0.02	_	% of FSR	Code 0x000h
Offset Error Temperature Coefficient	V _{OS} /°C	-	-5	_	ppm/°C	+25°C to +125°C
Gain Error	9 _E	_	-0.10	—	% of FSR	Code 0xFFFh, not including offset error
Gain Error Temperature Coefficient	Δ G/°C	_	-3	_	ppm/°C	
Internal Voltage Reference (V	/ _{REF})					•
Nominal Reference Voltage	V _{REF}	—	2.048	_	V	V_{OUTA} when G = 1x and Code = 0xFFFh
Temperature Coefficient	ΔV_{REF} /°C		125	_	ppm/°C	-40°C to 0°C
(Note 1)			0.25	_	LSb/°C	-40°C to 0°C
			45	_	ppm/°C	0°C to +85°C
		_	0.09	_	LSb/°C	0°C to +85°C
Output Noise (V _{REF} Noise)	E _{NREF} (0.1 - 10 Hz)	_	290	_	μV _{p-p}	Code = 0xFFFh, G = 1
Output Noise Density	e _{NREF} (1 kHz)	_	1.2	_	µV/√Hz	Code = 0xFFFh, G = 1
	e _{NREF} (10 kHz)	—	1.0	_	µV/√Hz	Code = 0xFFFh, G = 1
1/f Corner Frequency	f _{CORNER}	_	400	_	Hz	
Output Amplifier						•
Output Swing	V _{OUT}	-	0.010 to V _{DD} -0.040	—		Accuracy is better than 1 LSb for $V_{OUT} = 10 \text{ mV}$ to $(V_{DD} - 40 \text{ mV})$
Phase Margin	PM		66		0	
Slew Rate	SR	_	0.55	_	V/µs	
Short Circuit Current	I _{SC}	_	17	_	mA	
Settling Time	t _{SETTLING}	_	4.5	—	μs	Within 1/2 LSb of final value from 1/4 to 3/4 full-scale range
Dynamic Performance					•	·
DAC-to-DAC Crosstalk		_	<10	_	nV-s	Note 2
Major Code Transition Glitch		—	45	_	nV-s	1 LSb change around major carry (01111111 to 10000000)
Digital Feedthrough		_	<10	_	nV-s	Note 2
Analog Crosstalk		_	<10	_	nV-s	Note 2

Note 1: By design, not production tested.

AC CHARACTERISTICS (SPI™ TIMING SPECIFICATIONS)

Electrical Specifications: Unless otherwise indicated, V_{DD} = 2.7V – 5.5V, T_A = -40 to +125°C. Typical values are at +25°C.

Typical values are at +25°C.			22			
Parameters	Sym	Min	Тур	Max	Units	Conditions
Schmitt Trigger High-Level Input Voltage (All digital input pins)	V _{IH}	0.7 V _{DD}		_	V	
Schmitt Trigger Low-Level Input Voltage (All digital input pins)	V _{IL}		_	0.2 V _{DD}	V	
Hysteresis of Schmitt Trigger Inputs	V _{HYS}	—	0.05 V _{DD}	_		
Input Leakage Current	I _{LEAKAGE}	-1	_	1	μA	$\overline{SHDN} = \overline{LDAC} = \overline{CS} = SDI =$ SCK + V _{REF} = V _{DD} or AV _{SS}
Digital Pin Capacitance (All inputs/outputs)	C _{IN} , C _{OUT}	_	10	_	pF	V _{DD} = 5.0V, T _A = +25°C, f _{CLK} = 1 MHz (Note 1)
Clock Frequency	F _{CLK}	—	—	20	MHz	T _A = +25°C (Note 1)
Clock High Time	t _{HI}	15	—	_	ns	Note 1
Clock Low Time	t _{LO}	15	—	_	ns	Note 1
CS Fall to First Rising CLK Edge	t _{CSSR}	40	—	—	ns	Applies only when \overline{CS} falls with CLK high. (Note 1)
Data Input Setup Time	t _{SU}	15	_	_	ns	Note 1
Data Input Hold Time	t _{HD}	10	_	_	ns	Note 1
SCK Rise to \overline{CS} Rise Hold Time	^t снs	15		—	ns	Note 1
CS High Time	t _{CSH}	15	—	—	ns	Note 1
LDAC Pulse Width	t _{LD}	100	—	—	ns	Note 1
LDAC Setup Time	t _{LS}	40	—	—	ns	Note 1
SCK Idle Time before $\overline{\text{CS}}$ Fall	t _{IDLE}	40	_	—	ns	Note 1

Note 1: By design and characterization, not production tested.





SPI™ Input Timing.

TEMPERATURE CHARACTERISTICS

Electrical Specifications: Unless otherwise indicated, $V_{DD} = +2.7V$ to +5.5V, $AV_{SS} = GND$.								
Parameters	Sym	Min	Тур	Max	Units	Conditions		
Temperature Ranges								
Specified Temperature Range	T _A	-40	_	+125	°C			
Operating Temperature Range	Τ _Α	-40	_	+125	°C	Note 1		
Storage Temperature Range	T _A	-65	—	+150	°C			
Thermal Package Resistances								
Thermal Resistance, 8L-PDIP	θ_{JA}	_	85	—	°C/W			
Thermal Resistance, 8L-SOIC	θ_{JA}		163	—	°C/W			
Thermal Resistance, 8L-MSOP	θ _{JA}	_	206	—	°C/W			

Note 1: The MCP482X family of DACs operate over this extended temperature range, but with reduced performance. Operation in this range must not cause T_J to exceed the Maximum Junction Temperature of +150°C.

2.0 TYPICAL PERFORMANCE CURVES

Note: The graphs and tables provided following this note are a statistical summary based on a limited number of samples and are provided for informational purposes only. The performance characteristics listed herein are not tested or guaranteed. In some graphs or tables, the data presented may be outside the specified operating range (e.g., outside specified power supply range) and therefore outside the warranted range.

Note: Unless otherwise indicated, $T_A = +25^{\circ}C$, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, Gain = 2, $R_L = 5 \text{ k}\Omega$, $C_L = 100 \text{ pF}$.





DNL vs. Code.



FIGURE 2-2: DNL vs. Code and Ambient Temperature.



Temperature.

solute DINL VS. Amblen



FIGURE 2-4: Temperature.

INL vs. Code and Ambient



FIGURE 2-5: Temperature.

Absolute INL vs. Ambient



FIGURE 2-6: INL vs. Code.

Note: Single device graph for illustration of 64 code effect.

Note: Unless otherwise indicated, $T_A = +25^{\circ}C$, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, Gain = 2, $R_L = 5 k\Omega$, $C_L = 100 \text{ pF}$.



FIGURE 2-7: Full-Scale V_{OUTA} w/G = 1 (V_{REF}) vs. Ambient Temperature and V_{DD} .



FIGURE 2-8: Full-Scale V_{OUTA} w/G = 2 (2 V_{REF}) vs.Ambient Temperature and V_{DD} .



FIGURE 2-9: Output Noise Voltage Density (V_{REF} Noise Density w/G = 1) vs. Frequency.



FIGURE 2-10: Output Noise Voltage (V_{REF} Noise Voltage w/G = 1) vs. Bandwidth.

Note: Unless otherwise indicated, $T_A = +25^{\circ}C$, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, Gain = 2, $R_L = 5 \text{ k}\Omega$, $C_L = 100 \text{ pF}$.



FIGURE 2-11: MCP4821 I_{DD} vs. Ambient Temperature and V_{DD} .



FIGURE 2-12: MCP4821 I_{DD} Histogram (V_{DD} = 2.7V).



FIGURE 2-13: MCP4821 I_{DD} Histogram ($V_{DD} = 5.0V$).



FIGURE 2-14: MCP4822 I_{DD} vs. Ambient Temperature and V_{DD} .



FIGURE 2-15: MCP4822 I_{DD} Histogram (V_{DD} = 2.7V).



FIGURE 2-16: MCP4822 I_{DD} Histogram ($V_{DD} = 5.0$ V).

Note: Unless otherwise indicated, $T_A = +25^{\circ}C$, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, Gain = 2, $R_L = 5 k\Omega$, $C_L = 100 \text{ pF}$.



FIGURE 2-17: Hardware Shutdown Current vs. Ambient Temperature and V_{DD}.



FIGURE 2-18: Software Shutdown Current vs. Ambient Temperature and V_{DD}.



FIGURE 2-19: Offset Error vs. Ambient Temperature and V_{DD}.



FIGURE 2-20: Gain Error vs. Ambient Temperature and V_{DD}.



FIGURE 2-21: V_{IN} High Threshold vs. Ambient Temperature and V_{DD} .



FIGURE 2-22: V_{IN} Low Threshold vs. Ambient Temperature and V_{DD} .

Note: Unless otherwise indicated, $T_A = +25^{\circ}C$, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, Gain = 2, $R_L = 5 k\Omega$, $C_L = 100 pF$.



FIGURE 2-23: Input Hysteresis vs. Ambient Temperature and V_{DD}.



FIGURE 2-24: V_{OUT} High Limit vs. Ambient Temperature and V_{DD} .



FIGURE 2-25: V_{OUT} Low Limit vs. Ambient Temperature and V_{DD}.



FIGURE 2-26: I_{OUT} High Short vs. Ambient Temperature and V_{DD} .



FIGURE 2-27: I_{OUT} vs. V_{OUT} . Gain = 2.

MCP4821/MCP4822

Note: Unless otherwise indicated, $T_A = +25^{\circ}C$, $V_{DD} = 5V$, $AV_{SS} = 0V$, $V_{REF} = 2.048V$, Gain = 2, $R_L = 5 k\Omega$, $C_L = 100 \text{ pF}$.



FIGURE 2-28: V_{OUT} Rise Time 100%.





V_{OUT} Fall Time.



FIGURE 2-30:

V_{OUT} Rise Time 50%.





FIGURE 2-32: V_{OUT} Rise Time Exit Shutdown.



FIGURE 2-33: PSRR vs. Frequency.

3.0 PIN DESCRIPTIONS

The descriptions of the pins are listed in Table 3-1.

TABLE 3-1: PIN FUNCTION TABLE

MCP4821 Pin No.	MCP4822 Pin No.	Symbol	Function
1	1	V _{DD}	Positive Power Supply Input (2.7V to 5.5V)
2	2	CS	Chip Select Input
3	3	SCK	Serial Clock Input
4	4	SDI	Serial Data Input
5	5	LDAC	Synchronization input used to transfer DAC settings from serial latches to output latches
6	—	SHDN	Hardware Shutdown Input
	6	V _{OUTB}	DAC _B Output
7	7	AV _{SS}	Analog Ground
8	8	V _{OUTA}	DAC _A Output

3.1 Positive Power Supply Input (V_{DD})

 V_{DD} is the positive power supply input. The input power supply is relative to AV_{SS} and can range from 2.7V to 5.5V. A decoupling capacitor on V_{DD} is recommended to achieve maximum performance.

3.2 Chip Select (CS)

CS is the chip select input, which requires an active-low signal to enable serial clock and data functions.

3.3 Serial Clock Input (SCK)

SCK is the SPI compatible serial clock input.

3.4 Serial Data Input (SDI)

SDI is the SPI compatible serial data input.

3.5 Latch DAC Input (LDAC)

 $\overline{\text{LDAC}}$ (the latch DAC synchronization input) transfers the input latch registers to the DAC registers (output latches) when low. Can also be tied low if transfer on the rising edge of $\overline{\text{CS}}$ is desired.

3.6 Hardware Shutdown Input (SHDN)

SHDN is the hardware shutdown input that requires an active-low input signal to configure the DACs in their low-power Standby mode.

3.7 DAC_x Outputs (V_{OUTA}, V_{OUTB})

 V_{OUTA} and V_{OUTB} are DAC outputs. The DAC output amplifier drives these pins with a range of AV_{SS} to V_{DD}.

3.8 Analog Ground (AV_{SS})

 $\mathsf{AV}_{\mathsf{SS}}$ is the analog ground pin.

4.0 GENERAL OVERVIEW

The MCP482X devices are voltage-output string DACs. These devices include rail-to-rail output amplifiers, internal voltage reference, shutdown and reset-management circuitry. Serial communication conforms to the SPI protocol. The MCP482X devices operate from 2.7V to 5.5V supplies.

The coding of these devices is straight binary, with the ideal output voltage given by Equation 4-1, where *G* is the selected gain (1x or 2x), D_N represents the digital input value and *n* represents the number of bits of resolution (n = 12).

EQUATION 4-1: LSb SIZE

$V_{OUT} = \frac{2.048}{2}$	$\frac{V \cdot G \cdot D_N}{2^n}$
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1 LSb is the ideal voltage difference between two successive codes. Table 4-1 illustrates how to calculate LSb.

TABLE 4-1:	LSb SIZES
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Device	Gain	LSb Size
MCP482X	1x	2.048V/4096
MCP482X	2x	4.096V/4096

4.0.1 INL ACCURACY

INL error for these devices is the maximum deviation between an actual code transition point and its corresponding ideal transition point once offset and gain errors have been removed. These endpoints are from 0x000 to 0xFFF. Refer to Figure 4-1.

Positive INL represents transition(s) later than ideal. Negative INL represents transition(s) earlier than ideal.



FIGURE 4-1: INL Accuracy.

4.0.2 DNL ACCURACY

DNL error is the measure of variations in code widths from the ideal code width. A DNL error of zero would imply that every code is exactly 1 LSb wide.



FIGURE 4-2: DNL Accuracy.

4.0.3 OFFSET ERROR

Offset error is the deviation from zero voltage output when the digital input code is zero.

4.0.4 GAIN ERROR

Gain error is the deviation from the ideal output, $V_{REF} - 1$ LSb, excluding the effects of offset error.

4.1 Circuit Descriptions

4.1.1 OUTPUT AMPLIFIERS

The DACs' outputs are buffered with a low-power, precision CMOS amplifier. This amplifier provides low offset voltage and low noise. The output stage enables the device to operate with output voltages close to the power supply rails. Refer to **Section 1.0** "**Electrical Characteristics**" for range and load conditions.

In addition to resistive load-driving capability, the amplifier will also drive high capacitive loads without oscillation. The amplifiers' strong outputs allow V_{OUT} to be used as a programmable voltage reference in a system.

4.1.1.1 Programmable Gain Block

The rail-to-rail output amplifier has configurable gain, allowing optimal full-scale outputs for differing voltage reference inputs. The output amplifier gain has two selections, a gain of 1 V/V ($\overline{GA} = 1$) or a gain of 2 V/V ($\overline{GA} = 0$).

The output range is ideally 0.000V to 4095/4096 * 2.048V when G = 1, and 0.000 to 4095/4096 * 4.096V when G = 2. The default value for this bit is a gain of 2, yielding an ideal full-scale output of 0.000V to 4.096V due to the internal 2.048V V_{REF}. Note that the near rail-to-rail CMOS output buffer's ability to approach AV_{SS} and V_{DD} establish practical range limitations. The output swing specification in **Section 1.0 "Electrical Characteristics"** defines the range for a given load condition.

4.1.2 VOLTAGE REFERENCE

The MCP482X devices utilize internal 2.048V voltage reference. The voltage reference has low temperature coefficient and low noise characteristics. Refer to **Section 1.0 "Electrical Characteristics"** for the voltage reference specifications.

4.1.3 POWER-ON RESET CIRCUIT

The Power-On Reset (POR) circuit ensures that the DACs power-up with $\overline{SHDN} = 0$ (high-impedance). The devices will continue to have a high-impedance output until a valid Write command is performed to either of the DAC registers and the LDAC pin meets the input low threshold.

If the power supply voltage is less than the POR threshold ($V_{POR} = 2.0V$, typical), the DACs will be held in their reset state. They will remain in that state until $V_{DD} > V_{POR}$ and a subsequent Write command is received.

Figure 4-3 shows a typical power supply transient pulse and the duration required to cause a reset to occur, as well as the relationship between the duration and trip voltage. A 0.1 μ F decoupling capacitor, mounted as close as possible to the V_{DD} pin, provides additional transient immunity.



FIGURE 4-3: Typical Transient Response.

4.1.4 SHUTDOWN MODE

Shutdown mode can be entered by using either hardware or software commands. The hardware pin (SHDN) is only available on the MCP4821. During Shutdown mode, the supply current is isolated from most of the internal circuitry. The serial interface remains active, thus allowing a Write command to bring the device out of Shutdown mode. When the output amplifiers are shut down, the feedback resistance (typically 500 kΩ) produces a high-impedance path to AV_{SS} . The device will remain in Shutdown mode until the SHDN pin is brought high and a write command with $\overline{SD} = 1$ is latched into the device. When a DAC is changed from Shutdown to Active mode, the output settling time takes < 10 µs, but greater than the standard Active mode settling time (4.5 µs).

5.0 SERIAL INTERFACE

5.1 Overview

The MCP482X family is designed to interface directly with the SPI port, available on many microcontrollers, and supports Mode 0,0 and Mode 1,1. Commands and data are sent to the device via the SDI pin, with data being clocked-in on the rising edge of SCK. The communications are unidirectional and, thus, data cannot be read out of the MCP482X devices. The CS pin must be held low for the duration of a write command. The write command consists of 16 bits and is used to configure the DAC's control and data latches. Register 5-1 details the input registers used to configure and load the DAC_A and DAC_B registers. Refer to Figure 1-1 and the AC Electrical Characteristics tables for detailed input and output timing specifications for both Mode 0,0 and Mode 1,1 operation.

5.2 Write Command

The write command is initiated by driving the \overline{CS} pin low, followed by clocking the four configuration bits and the 12 data bits into the SDI pin on the rising edge of SCK. The \overline{CS} pin is then raised, causing the data to be latched into the selected DAC's input registers. The MCP482X devices utilize a double-buffered latch structure to allow both DAC_A's and DAC_B's outputs to be synchronized with the LDAC pin, if desired. Upon the LDAC pin achieving a low state, the values held in the DAC's input registers are transferred into the DACs' output registers. The outputs will transition to the value and held in the DAC_X register.

All writes to the MCP482X devices are 16-bit words. Any clocks past 16 will be ignored. The most significant four bits are configuration bits. The remaining 12 bits are data bits. No data can be transferred into the device with \overline{CS} high. This transfer will only occur if 16 clocks have been transferred into the device. If the rising edge of \overline{CS} occurs prior, shifting of data into the input registers will be aborted.

REGISTER 5-1: WRITE COMMAND REGISTER

Upper Half	:						
W-x	W-x	W-x	W-0	W-x	W-x	W-x	W-x
Ā/B	_	GA	SHDN	D11	D10	D9	D8
bit 15 bit 8							

Lower Half	:						
W-x	W-x	W-x	W-x	W-x	W-x	W-x	W-x
D7	D6	D5	D4	D3	D2	D1	D0
bit 7				•	•		bit

- bit 15 $\overline{A/B}$: DAC_A or DAC_B Select bit
 - $1 = Write to DAC_B$
 - $o = Write to DAC_A$
- bit 14 Don't Care

bit 12

- bit 13 **GA:** Output Gain Select bit
 - $1 = 1x (V_{OUT} = V_{REF} * D/4096)$
 - $0 = 2x (V_{OUT} = 2 * V_{REF} * D/4096)$

SHDN: Output Power-down Control bit

- 1 = Output Power-down Control bit
- = Output buffer disabled, Output is high-impedance

```
bit 11-0 D11:D0: DAC Data bits
12-bit number "D" which sets the output value. Contains a value between 0 and 4095.
```

Legend			
R = Readable bit	W = Writable bit	U = Unimplemented b	it, read as '0'
-n = Value at POR	1 = bit is set	0 = bit is cleared	x = bit is unknown



FIGURE 5-1: Write Command.

6.0 TYPICAL APPLICATIONS

The MCP482X devices are general purpose DACs intended to be used in applications where a precision, low-power DAC with moderate bandwidth and internal voltage reference is required.

Applications generally suited for the MCP482X devices include:

- Set Point or Offset Trimming
- Sensor Calibration
- Precision Selectable Voltage Reference
- Portable Instrumentation (Battery-Powered)
- Calibration of Optical Communication Devices

6.1 Digital Interface

The MCP482X devices utilize a 3-wire synchronous serial protocol to transfer the DACs' setup and output values from the digital source. The serial protocol can be interfaced to SPI™ or Microwire peripherals common on many microcontroller units (MCUs), including Microchip's PICmicro[®] MCUs and dsPIC[®] DSC family of MCUs. In addition to the three serial connections (CS, SCK and SDI), the LDAC signal synchronizes when the serial settings are latched into the DAC's output from the serial input latch. Figure 6-1 illustrates the required connections. Note that LDAC is active-low. If desired, this input can be tied low to reduce the required connections from 4 to 3. Write commands will be latched directly into the output latch when a valid 16 clock transmission has been received and \overline{CS} has been raised.

6.2 Power Supply Considerations

The typical application will require a bypass capacitor in order to filter high-frequency noise. The noise can be induced onto the power supply's traces or as a result of changes on the DAC's output. The bypass capacitor helps to minimize the effect of these noise sources on signal integrity. Figure 6-1 illustrates an appropriate bypass strategy.

In this example, the recommended bypass capacitor value is 0.1 $\mu F.$ This capacitor should be placed as close to the device power pin (V_DD) as possible (within 4 mm).

The power source supplying these devices should be as clean as possible. If the application circuit has separate digital and analog power supplies, AV_{DD} and AV_{SS} should reside on the analog plane.

6.3 Output Noise Considerations

The voltage noise density (in $\mu V/\sqrt{Hz}$) is illustrated in Figure 2-9. This noise appears at V_{OUTX}, and is primarily a result of the internal reference voltage. Its 1/f corner (f_{CORNER}) is approximately 400 Hz.

Figure 2-10 illustrates the voltage noise (in mV_{RMS} or mV_{P-P}). A small bypass capacitor on V_{OUTX} is an effective method to produce a single-pole Low-Pass Filter (LPF) that will reduce this noise. For instance, a bypass capacitor sized to produce a 1 kHz LPF would result in an E_{NREF} of about 100 μ V_{RMS}. This would be necessary when trying to achieve the low DNL performance (at G = 1) that the MCP482X devices are capable of. The tested range for stability is .001µF thru 4.7 µF.



FIGURE 6-1: Typical Connection Diagram.

6.4 Layout Considerations

Inductively-coupled AC transients and digital switching noise can degrade the output signal integrity, MCP482X potentially masking the family's performance. Careful board layout will minimize these effects and increase the Signal-to-Noise Ratio (SNR). Bench testing has shown that a multi-layer board utilizing a low-inductance ground plane, isolated inputs, isolated outputs and proper decoupling are critical to achieving the performance that the MCP482X devices are capable of providing. Particularly harsh environments may require shielding of critical signals.

Breadboards and wire-wrapped boards are not recommended if low noise is desired.

6.5 Single-Supply Operation

The MCP482X devices are Rail-to-Rail (R-R) input and output DACs designed to operate with a V_{DD} range of 2.7V to 5.5V. Its output amplifier is robust enough to drive common, small-signal loads directly, thus eliminating the cost and size of an external buffer for most applications.

6.5.1 DC SET POINT OR CALIBRATION

A common application for a DAC with the MCP482X family's performance is a digitally-controlled set point and/or calibration of variable parameters, such as sensor offset or slope. 12-bit resolution provides 4096 output steps. If G = 1 is selected, then the internal 2.048 V_{REF} would produce 500 μ V of resolution. If G = 2 is selected, the internal 2.048 V_{REF} would produce 1 mV of resolution.

6.5.1.1 Decreasing The Output Step Size

If the application is calibrating the threshold of a diode, transistor or resistor tied to AV_{SS}, a threshold range of 0.8V may be desired to provide 200 µV resolution. Two common methods to achieve a 0.8V range is to either reduce V_{RFF} to 0.82V (would require MCP492X device and external voltage reference) or use a voltage divider on the DAC's output. Typically, when using a lowvoltage V_{REF}, the noise floor causes SNR error that is intolerable. The voltage divider method provides some advantages when V_{RFF} needs to be very low or when the desired output voltage is not available. Using two resistors to scale the output range down to the precise desired level is a simple, low-cost method to achieve very small step sizes. Example 6-1 illustrates this concept. Note that the bypass capacitor on the output of the voltage divider plays a critical function in attenuating the output noise of the DAC and the induced noise from the environment.

The MCP482X family's low ± 0.75 (max.) DNL performance is critical to meeting calibration accuracy in production.



EXAMPLE 6-1: Set Point or Threshold Calibration.

6.5.1.2 Building a "Window" DAC

When calibrating a set point or threshold of a sensor, rarely does the sensor utilize the entire output range of the DAC. If the LSb size is adequate to meet the application's accuracy needs, the resolution is sacrificed without consequences. If greater accuracy is needed, then the output range will need to be reduced to increase the resolution around the desired threshold. If the threshold is not near V_{REF} , $2V_{REF}$ or AV_{SS}, then

creating a "window" around the threshold has several advantages. One simple method to create this "window" is to use a voltage divider network with a pullup and pull-down resistor. Example 6-2 and Example 6-4 illustrates this concept.

The MCP482X family's low ± 0.75 (max.) DNL performance is critical to meet calibration accuracy in production.



EXAMPLE 6-2: Single-Supply "Window" DAC.

6.6 Bipolar Operation

Bipolar operation is achievable using the MCP482X devices by using an external operational amplifier (op amp). This configuration is desirable due to the wide variety and availability of op amps. This allows a general purpose DAC, with its cost and availability advantages, to meet almost any desired output voltage range, power and noise performance.

Example 6-3 illustrates a simple bipolar voltage source configuration. R₁ and R₂ allow the gain to be selected, while R₃ and R₄ shift the DAC's output to a selected offset. Note that R4 can be tied to V_{DD}, instead of AV_{SS}, if a higher offset is desired. Note that a pull-up to V_{DD} could be used, instead of R₄ or in addition to R₄, if a higher offset is desired.





6.6.1 DESIGN A BIPOLAR DAC USING EXAMPLE 6-3

An output step magnitude of 1 mV, with an output range of $\pm 2.05V$, is desired for a particular application.

- 1. Calculate the range: +2.05V (-2.05V) = 4.1V.
- Calculate the resolution needed: 4.1V/1 mV = 4100

Since $2^{12} = 4096$, 12-bit resolution is desired.

3. The amplifier gain (R_2/R_1) , multiplied by fullscale V_{OUT} (4.096V), must be equal to the desired minimum output to achieve bipolar operation. Since any gain can be realized by choosing resistor values (R_1+R_2) , the V_{REF} value must be selected first. If a V_{REF} of 4.096V is used (G=2), solve for the amplifier's gain by setting the DAC to 0, knowing that the output needs to be -2.05V. The equation can be simplified to:

$$\frac{-R_2}{R_1} = \frac{-2.05}{4.096V} \qquad \qquad \frac{R_2}{R_1} = \frac{1}{2}$$

If $R_1 = 20 \text{ k}\Omega$ and $R_2 = 10 \text{ k}\Omega$, the gain will be 0.5

4. Next, solve for R_3 and R_4 by setting the DAC to 4096, knowing that the output needs to be +2.05V.

$$\frac{R_4}{(R_3 + R_4)} = \frac{2.05V + (0.5 \cdot 4.096V)}{1.5 \cdot 4.096V} = \frac{2}{3}$$

If R₄ = 20 kΩ, then R₃ = 10 kΩ

6.7 Selectable Gain and Offset Bipolar Voltage Output Using A Dual DAC

In some applications, precision digital control of the output range is desirable. Example 6-4 illustrates how to use the MCP482X family to achieve this in a bipolar or single-supply application.

This circuit is typically used for linearizing a sensor whose slope and offset varies.

The equation to design a bipolar "window" DAC would be utilized if R_3 , R_4 and R_5 are populated.



EXAMPLE 6-4: Bipolar Voltage Source with Selectable Gain and Offset.

6.8 Designing A Double-Precision DAC Using A Dual DAC

Example 6-5 illustrates how to design a single-supply voltage output capable of up to 24-bit resolution from a dual 12-bit DAC. This design is simply a voltage divider with a buffered output.

As an example, if a similar application to the one developed in Section 6.6.1 "Design a Bipolar DAC Using Example 6-3" required a resolution of 1 μ V instead of 1 mV, and a range of 0V to 4.1V, then 12-bit resolution would not be adequate.

- 1. Calculate the resolution needed: $4.1V/1 \mu V = 4.1e06$. Since $2^{22} = 4.2e06$, 22-bit resolution is desired. Since DNL = ±0.75 LSb, this design can be attempted with the MCP482X family.
- 2. Since DAC_B 's V_{OUTB} has a resolution of 1 mV, its output only needs to be "pulled" 1/1000 to meet the 1 μ V target. Dividing V_{OUTA} by 1000 would allow the application to compensate for DAC_B 's DNL error.
- 3. If R_2 is 100 Ω , then R_1 needs to be 100 k Ω .
- 4. The resulting transfer function is shown in the equation of Example 6-5.



EXAMPLE 6-5: Simple, Double-Precision DAC.

6.9 Building A Programmable Current Source

Example 6-6 illustrates a variation on a voltage follower design where a sense resistor is used to convert the DAC's voltage output into a digitally-selectable current source.

Adding the resistor network from Example 6-2 would be advantageous in this application. The smaller R_{SENSE} is, the less power dissipated across it. However, this also reduces the resolution that the current can be controlled with. The voltage divider, or "window", DAC configuration would allow the range to be reduced, thus increasing resolution around the range of interest. When working with very small sensor voltages, plan on eliminating the amplifier's offset error by storing the DAC's setting under known sensor conditions.



EXAMPLE 6-6: Digitally-Controlled Current Source.

7.0 DEVELOPMENT SUPPORT

7.1 Evaluation & Demonstration Boards

The Mixed Signal PICtail[™] Demo Board supports the MCP482X family of devices. Refer to www.microchip.com for further information on this product's capabilities and availability.

7.2 Application Notes

Application notes illustrating the performance and implementation of the MCP482X family are planned but are currently not released. Refer to www.microchip.com for further information.

8.0 PACKAGING INFORMATION

8.1 Package Marking Information

8-Lead MSOP



8-Lead PDIP (300 mil)

$\underline{\Gamma} \underline{C} \underline{C} \underline{C}$
XXXXXXXX
XXXXXNNN

8-Lead SOIC (150 mil)



Example:







Leg	jend:	XXX Y YY WW NNN @3 *	Customer-specific information Year code (last digit of calendar year) Year code (last 2 digits of calendar year) Week code (week of January 1 is week '01') Alphanumeric traceability code Pb-free JEDEC designator for Matte Tin (Sn) This package is Pb-free. The Pb-free JEDEC designator (e3) can be found on the outer packaging for this package.
Not	b	e carried	nt the full Microchip part number cannot be marked on one line, it will d over to the next line, thus limiting the number of available s for customer-specific information.

8-Lead Plastic Micro Small Outline Package (MS) (MSOP)





	Units				M	ILLIMETERS'	
Dimension I	_imits	MIN	NOM	MAX	MIN	NOM	MAX
Number of Pins	n		8			8	
Pitch	р		.026 BSC			0.65 BSC	
Overall Height	A	-	-	.043	-	-	1.10
Molded Package Thickness	A2	.030	.033	.037	0.75	0.85	0.95
Standoff	A1	.000	-	.006	0.00	-	0.15
Overall Width	E		.193 TYP.		4.90 BSC		
Molded Package Width	E1		.118 BSC		3.00 BSC		
Overall Length	D		.118 BSC			3.00 BSC	
Foot Length	L	.016	.024	.031	0.40	0.60	0.80
Footprint (Reference)	F		.037 REF			0.95 REF	
Foot Angle	φ	0°	-	8°	0°	-	8°
Lead Thickness	С	.003	.006	.009	0.08	-	0.23
Lead Width	В	.009	.012	.016	0.22	-	0.40
Mold Draft Angle Top	α	5 ⁵ °	-	15°	5°	-	15°
Mold Draft Angle Bottom	β	5 ^{5°}	Ξ.	15°	5°	-	15°
*Controlling Parameter							

*Controlling Parameter

Notes:

Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed .010" (0.254mm) per side.

JEDEC Equivalent: MO-187

Drawing No. C04-111

8-Lead Plastic Dual In-line (P) – 300 mil (PDIP)







	Units				MILLIMETERS		
Dimensi	on Limits	MIN	NOM	MAX	MIN	NOM	MAX
Number of Pins	n		8			8	
Pitch	р		.100			2.54	
Top to Seating Plane	A	.140	.155	.170	3.56	3.94	4.32
Molded Package Thickness	A2	.115	.130	.145	2.92	3.30	3.68
Base to Seating Plane	A1	.015			0.38		
Shoulder to Shoulder Width	Е	.300	.313	.325	7.62	7.94	8.26
Molded Package Width	E1	.240	.250	.260	6.10	6.35	6.60
Overall Length	D	.360	.373	.385	9.14	9.46	9.78
Tip to Seating Plane	L	.125	.130	.135	3.18	3.30	3.43
Lead Thickness	С	.008	.012	.015	0.20	0.29	0.38
Upper Lead Width	B1	.045	.058	.070	1.14	1.46	1.78
Lower Lead Width	В	.014	.018	.022	0.36	0.46	0.56
Overall Row Spacing	§ eB	.310	.370	.430	7.87	9.40	10.92
Mold Draft Angle Top	α	5	10	15	5	10	15
Mold Draft Angle Bottom	β	5	10	15	5	10	15

* Controlling Parameter § Significant Characteristic

Notes:

Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed .010" (0.254mm) per side.

JEDEC Equivalent: MS-001 Drawing No. C04-018

8-Lead Plastic Small Outline (SN) - Narrow, 150 mil (SOIC)









Limits n p A A2	MIN .053	NOM 8 .050 .061	MAX	MIN	NOM 8 1.27	MAX
p A A2		.050	000		-	
A A2			000		1 27	
A2		.061	000		1.27	
	052		.069	1.35	1.55	1.75
	.052	.056	.061	1.32	1.42	1.55
A1	.004	.007	.010	0.10	0.18	0.25
E	.228	.237	.244	5.79	6.02	6.20
E1	.146	.154	.157	3.71	3.91	3.99
D	.189	.193	.197	4.80	4.90	5.00
h	.010	.015	.020	0.25	0.38	0.51
L	.019	.025	.030	0.48	0.62	0.76
φ	0	4	8	0	4	8
С	.008	.009	.010	0.20	0.23	0.25
В	.013	.017	.020	0.33	0.42	0.51
α	0	12	15	0	12	15
β	0	12	15	0	12	15
	A1 E E1 D h L ¢ C B α	A1 .004 E .228 E1 .146 D .189 h .010 L .019 φ 0 c .008 B .013 α 0	A1 .004 .007 E .228 .237 E1 .146 .154 D .189 .193 h .010 .015 L .019 .025 φ 0 4 c .008 .009 B .013 .017 α 0 12	A1 .004 .007 .010 E .228 .237 .244 E1 .146 .154 .157 D .189 .193 .197 h .010 .015 .020 L .019 .025 .030 φ 0 4 8 c .008 .009 .010 B .013 .017 .020 α 0 12 15	A1.004.007.0100.10E.228.237.2445.79E1.146.154.157.3.71D.189.193.1974.80h.010.015.0200.25L.019.025.0300.48 ϕ 0480c.008.009.0100.20B.013.017.0200.33 α 012150	A1.004.007.0100.100.18E.228.237.2445.796.02E1.146.154.1573.713.91D.189.193.1974.804.90h.010.015.0200.250.38L.019.025.0300.480.62 ϕ 04804c.008.009.0100.200.23B.013.017.0200.330.42 α 01215012

* Controlling Parameter

§ Significant Characteristic

Notes:

Dimensions D and E1 do not include mold flash or protrusions. Mold flash or protrusions shall not exceed .010" (0.254mm) per side. JEDEC Equivalent: MS-012 Drawing No. C04-057

APPENDIX A: REVISION HISTORY

Revision A (June 2005)

• Original Release of this Document.

MCP4821/4822

NOTES:

PRODUCT IDENTIFICATION SYSTEM

To order or obtain information, e.g., on pricing or delivery, refer to the factory or the listed sales office.

PART NO.	<u>× /xx</u>	Examples:
	perature Package Inge	a) MCP4821T-E/SN: Tape and Reel Extended Temperature, 8LD SOIC package. b) MCP4821T-E/MS: Tape and Reel
Device:	MCP4821:12-Bit DAC with SPI™ InterfaceMCP4821T:12-Bit DAC with SPI Interface (Tape and Reel) (SOIC, MSOP)MCP4822:12-Bit DAC with SPI InterfaceMCP4822T:12-Bit DAC with SPI Interface (Tape and Reel) (SOIC, MSOP)	 Extended Temperature, 8LD MSOP package. c) MCP4821-E/SN: Extended Temperature, 8LD SOIC package. d) MCP4821-E/MS: Extended Temperature, 8LD MSOP package. e) MCP4821-E/P: Extended Temperature, 8LD PDIP package.
Temperature Range:	$E = -40^{\circ}C \text{ to } +125^{\circ}C$	a) MCP4822T-E/SN: Tape and Reel Extended Temperature, 8LD SOIC package.
Package:	MS = Plastic MSOP, 8-lead P = Plastic DIP (300 mil Body), 8-lead SN = Plastic SOIC, (150 mil Body), 8-lead	b) MCP4822-E/P: Extended Temperature, 8LD PDIP package. c) MCP4822-E/SN: Extended Temperature, 8LD SOIC package.

MCP4821/4822

NOTES:

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